PD-95322

International **ICR** Rectifier

- Advanced Process Technology
- Surface Mount (IRF1310NS)
- Low-profile through-hole (IRF1310NL)
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

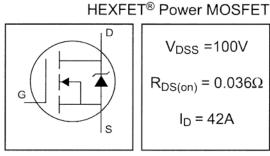
Description

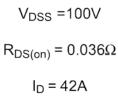
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

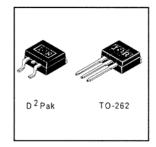
The D²Pak is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible onresistance in any existing surface mount package. The D²Pak is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

The through-hole version (IRF1310NL) is available for lowprofile applications.

Absolute Maximum Ratings







IRF1310NS/LPbF

	Parameter	Max.	Units	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V [®]	42		
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10VS	30	A	
I _{DM}	Pulsed Drain Current ①⑤	140		
$P_D@T_A = 25^{\circ}C$	Power Dissipation	3.8	W	
P _D @T _C = 25°C	Power Dissipation	160	W	
	Linear Derating Factor	1.1	W/°C	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy 25	420	mJ	
I _{AR}	Avalanche Current®	22	A	
E _{AR}	Repetitive Avalanche Energy®	16	mJ	
dv/dt	Peak Diode Recovery dv/dt 35	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T _{STG}	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		

Thermal Resistance

	Parameter	Тур.	Max.	Units
R _{0JC}	Junction-to-Case		0.95	80044
R _{NA}	Junction-to-Ambient (PCB Mounted, steady-state)**		40	°C/W

International **ISPR** Rectifier

Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250 \mu A$
ΔV(BR)DSS/ΔT	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I _D = 1mA®
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.036	Ω	V _{GS} = 10V, I _D = 22A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
9fs	Forward Transconductance	14			S	V _{DS} = 25V, I _D = 22AS
	Desig to Source Lookage Current			25	μA	$V_{DS} = 100V, V_{GS} = 0V$
DSS	Drain-to-Source Leakage Current			250	P.	V _{DS} = 80V, V _{GS} = 0V, T _J = 150°C
	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
GSS	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$
Qq	Total Gate Charge			110		I _D = 22A
Q _{gs}	Gate-to-Source Charge			15	nC	$V_{DS} = 80V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			58		V_{GS} = 10V, See Fig. 6 and 13 (4)
t _{d(on)}	Turn-On Delay Time		11			$V_{DD} = 50V$
tr	RiseTime		56			I _D = 22A
t _{d(off)}	Turn-Off Delay Time		45		ns	$R_G = 3.6\Omega$
tr	FallTime		40		1	R _D = 2.9Ω, See Fig. 10 ④ ⑤
1	Internal Source Inductance		7.5		- nH	Between lead,
Ls						and center of die contact
Ciss	Input Capacitance		1900			V _{GS} = 0V
Coss	Output Capacitance		450] pF	V _{DS} = 25V
Crss	Reverse Transfer Capacitance		230		1	f = 1.0MHz, See Fig. 5®

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
k	Continuous Source Current (Body Diode)			42		MOSFET symbol showing the
ISM	Pulsed Source Current (Body Diode) © ©			140	A	integral reverse p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	T _J = 25°C, I _S =22A, V _{GS} = 0V ④
t _{rr}	Reverse Recovery Time		180	270	ns	$T_J = 25^{\circ}C, I_F = 22A$
Qrr	Reverse Recovery Charge		1.2	1.8	μC	di/dt = 100A/µs ⊛⑤
t _{on}	Forward Turn-On Time	Intrinsic tum-on time is negligible (tum-on is dominated by $L_{S}+L_{D})$				

Notes:

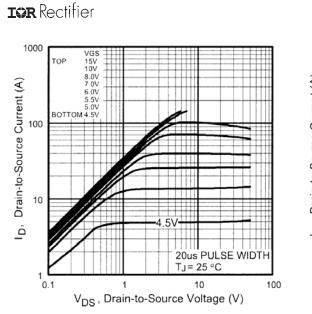
① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11) $\textcircled{\mbox{0}}$ Pulse width \leq 300µs; duty cycle \leq 2%.

- @ Starting T_J = 25°C, L = 1.7mH R_G = 25 $\Omega,\,I_{AS}$ = 22A. (See Figure 12)
- 3 I_{SD} \leq 22A, di/dt \leq 180A/µs, V_{DD} \leq V_{(BR)DSS}, T_{\rm J} \leq 175°C

© Uses IRF1310N data and test conditions

** When mounted on 1" square PCB (FR-4 or G-10 Material).

For recommended soldering techniques refer to application note #AN-994.



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Fig 1. Typical Output Characteristics

IRF1310NS/LPbF

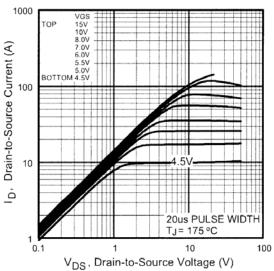


Fig 2. Typical Output Characteristics

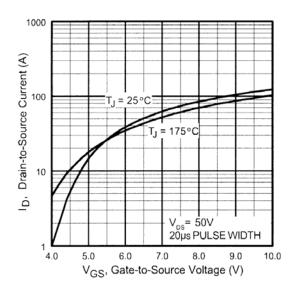


Fig 3. Typical Transfer Characteristics

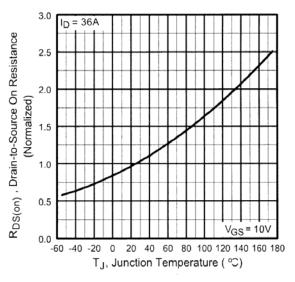
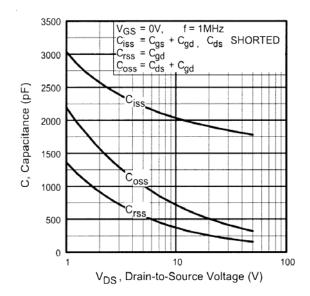
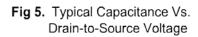


Fig 4. Normalized On-Resistance Vs. Temperature



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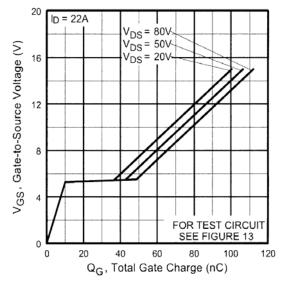


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

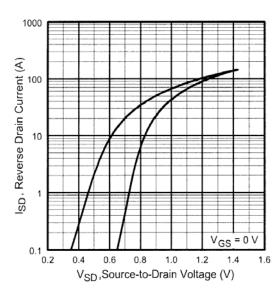


Fig 7. Typical Source-Drain Diode Forward Voltage

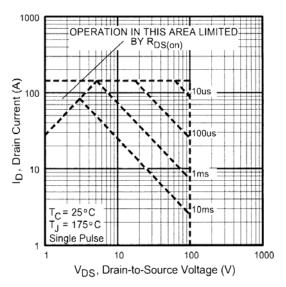
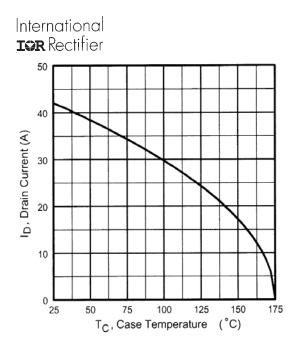
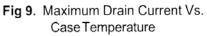


Fig 8. Maximum Safe Operating Area





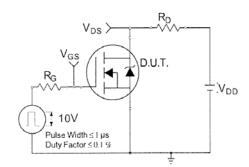


Fig 10a. Switching Time Test Circuit

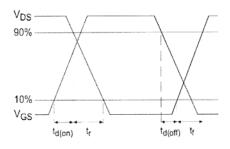


Fig 10b. Switching Time Waveforms

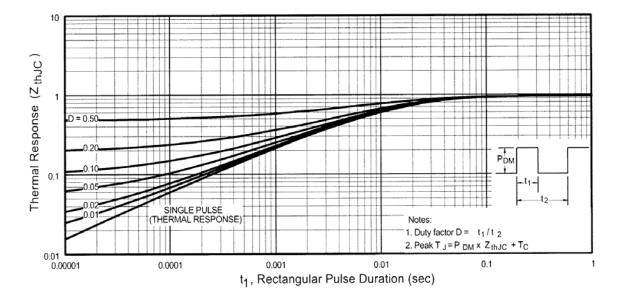


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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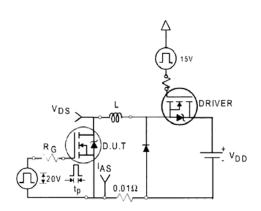


Fig 12a. Unclamped Inductive Test Circuit

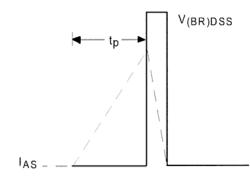


Fig 12b. Unclamped Inductive Waveforms

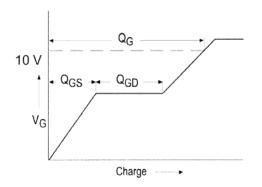
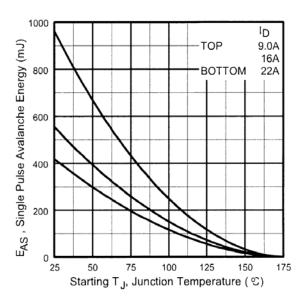
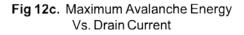


Fig 13a. Basic Gate Charge Waveform 6





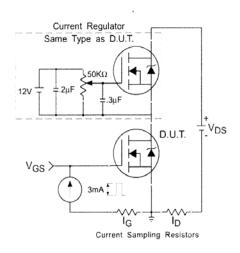


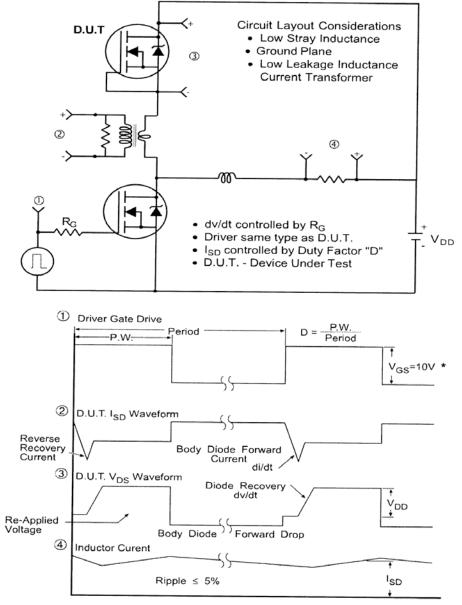
Fig 13b. Gate Charge Test Circuit

International **TOR** Rectifier

IRF1310NS/LPbF

Peak Diode Recovery dv/dt Test Circuit

Peak Diode Recovery dv/dt Test Circuit

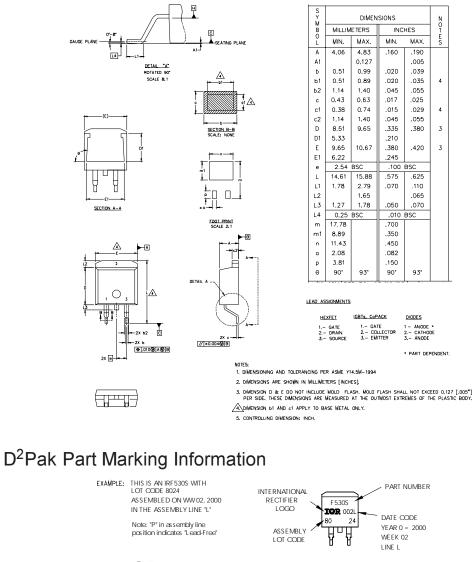


* V_{GS} = 5V for Logic Level Devices

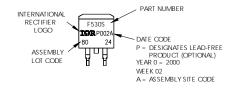
Fig 14. For N-Channel HEXFETS

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D²Pak Package Outline

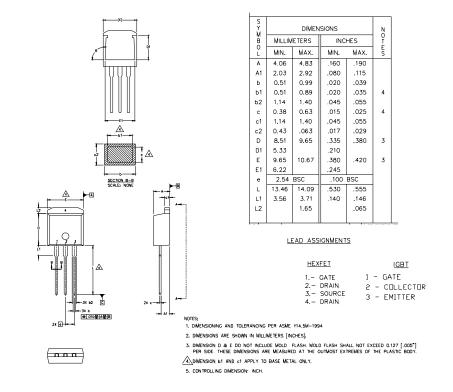


<u>OR</u>

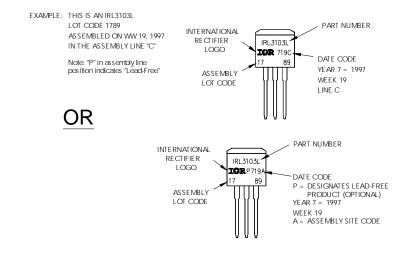


International **ICPR** Rectifier

TO-262 Package Outline



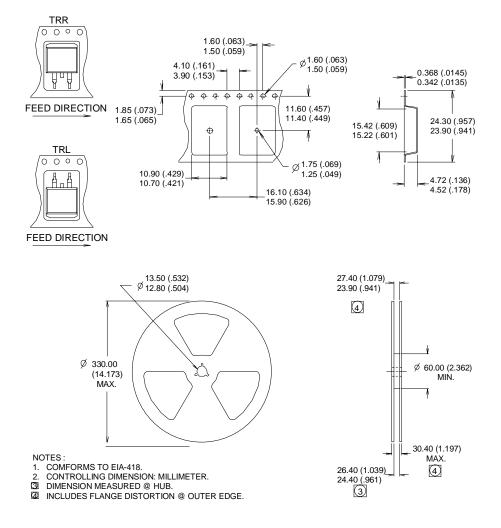
TO-262 Part Marking Information



International TOR Rectifier

D²Pak Tape & Reel Information

Dimensions are shown in millimeters (inches)



Data and specifications subject to change without notice.

International **ICR** Rectifier

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